

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	44	(measuring or detect\$3) near9 (((pattern or mark) or imprint\$3) near4 (film near2 substrate))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/12 12:19
L2	10	1 and defect	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/12 12:08
L3	0	1 and mold\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/12 12:08
L4	64293	(pattern or mark) near2 (head or device)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/12 12:18
L5	85	((measuring or detect\$3) near9 ((film near2 substrate))) and 4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/12 12:19